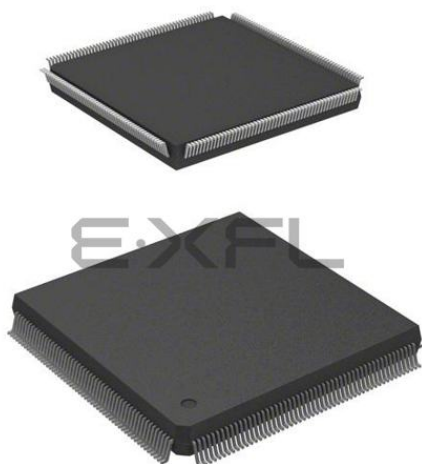




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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	176
Number of Gates	36000
Voltage - Supply	3V ~ 3.6V, 4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a42mx24-1pq208m

3.3.7 Low Power Mode

42MX devices have been designed with a Low Power Mode. This feature, activated with setting the special LP pin to HIGH for a period longer than 800 ns, is particularly useful for battery-operated systems where battery life is a primary concern. In this mode, the core of the device is turned off and the device consumes minimal power with low standby current. In addition, all input buffers are turned off, and all outputs and bidirectional buffers are tristated. Since the core of the device is turned off, the states of the registers are lost. The device must be re-initialized when exiting Low Power Mode. I/Os can be driven during LP mode, and clock pins should be driven HIGH or LOW and should not float to avoid drawing current. To exit LP mode, the LP pin must be pulled LOW for over 200 μ s to allow for charge pumps to power up, and device initialization will begin.

3.4 Power Dissipation

The general power consumption of MX devices is made up of static and dynamic power and can be expressed with the following equation.

3.4.1 General Power Equation

$$P = [ICC_{standby} + ICC_{active}] * V_{CCI} + IOL * VOL * N + IOH * (V_{CCI} - VOH) * M$$

EQ 1

where:

- $ICC_{standby}$ is the current flowing when no inputs or outputs are changing.
- ICC_{active} is the current flowing due to CMOS switching.
- IOL , IOH are TTL sink/source currents.
- VOL , VOH are TTL level output voltages.
- N equals the number of outputs driving TTL loads to VOL .
- M equals the number of outputs driving TTL loads to VOH .

Accurate values for N and M are difficult to determine because they depend on the family type, on design details, and on the system I/O. The power can be divided into two components: static and active.

3.4.2 Static Power Component

The static power due to standby current is typically a small component of the overall power consumption. Standby power is calculated for commercial, worst-case conditions. The static power dissipation by TTL loads depends on the number of outputs driving, and on the DC load current. For instance, a 32-bit bus sinking 4mA at 0.33V will generate 42mW with all outputs driving LOW, and 140mW with all outputs driving HIGH. The actual dissipation will average somewhere in between, as I/Os switch states with time.

3.4.3 Active Power Component

Power dissipation in CMOS devices is usually dominated by the dynamic power dissipation. Dynamic power consumption is frequency-dependent and is a function of the logic and the external I/O. Active power dissipation results from charging internal chip capacitances of the interconnect, unprogrammed antifuses, module inputs, and module outputs, plus external capacitances due to PC board traces and load device inputs. An additional component of the active power dissipation is the totem pole current in the CMOS transistor pairs. The net effect can be associated with an equivalent capacitance that can be combined with frequency and voltage to represent active power dissipation.

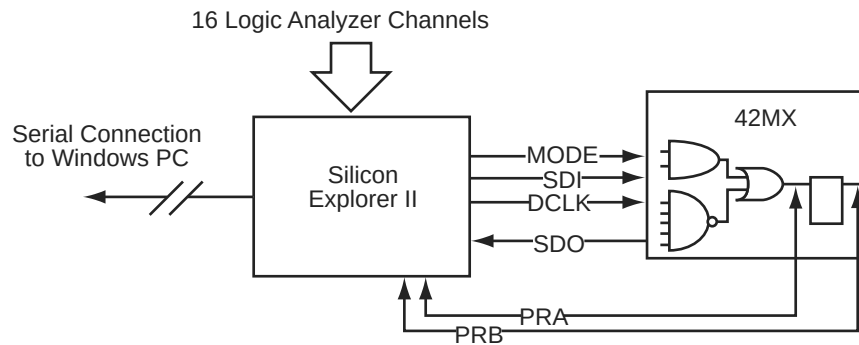
The power dissipated by a CMOS circuit can be expressed by the equation:

$$\text{Power}(\mu\text{W}) = C_{EQ} * V_{CCA}^2 * F(1)$$

EQ 2

where:

- C_{EQ} = Equivalent capacitance expressed in picofarads (pF)

Figure 13 • Silicon Explorer II Setup with 42MX**Table 8 • Device Configuration Options for Probe Capability**

Security Fuse(s) Programmed	Mode	PRA, PRB ¹	SDI, SDO, DCLK ¹
No	LOW	User I/Os ²	User I/Os ²
No	HIGH	Probe Circuit Outputs	Probe Circuit Inputs
Yes	–	Probe Circuit Secured	Probe Circuit Secured

1. Avoid using SDI, SDO, DCLK, PRA and PRB pins as input or bidirectional ports. Since these pins are active during probing, input signals will not pass through these pins and may cause contention.
2. If no user signal is assigned to these pins, they will behave as unused I/Os in this mode. See the Pin Descriptions, page 83 for information on unused I/O pins

3.4.7 Design Consideration

It is recommended to use a series 70Ω termination resistor on every probe connector (SDI, SDO, MODE, DCLK, PRA and PRB). The 70 Ω series termination is used to prevent data transmission corruption during probing and reading back the checksum.

3.4.8 IEEE Standard 1149.1 Boundary Scan Test (BST) Circuitry

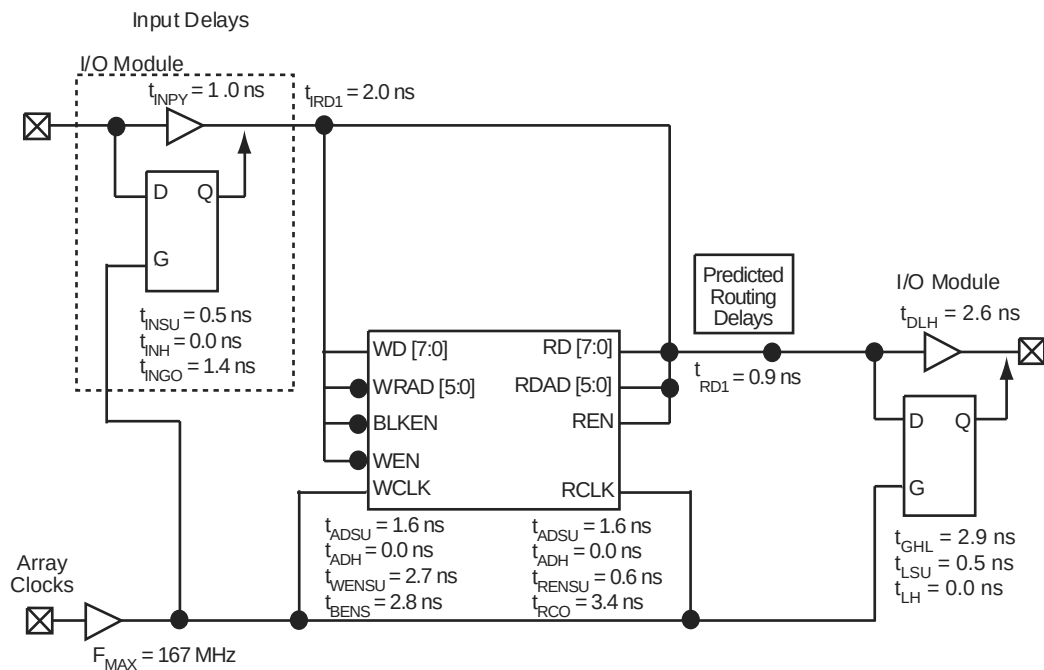
42MX24 and 42MX36 devices are compatible with IEEE Standard 1149.1 (informally known as Joint Testing Action Group Standard or JTAG), which defines a set of hardware architecture and mechanisms for cost-effective board-level testing. The basic MX boundary-scan logic circuit is composed of the TAP (test access port), TAP controller, test data registers and instruction register (Figure 14, page 18). This circuit supports all mandatory IEEE 1149.1 instructions (EXTEST, SAMPLE/PRELOAD and BYPASS) and some optional instructions. Table 9, page 18 describes the ports that control JTAG testing, while Table 10, page 18 describes the test instructions supported by these MX devices.

Each test section is accessed through the TAP, which has four associated pins: TCK (test clock input), TDI and TDO (test data input and output), and TMS (test mode selector).

The TAP controller is a four-bit state machine. The '1's and '0's represent the values that must be present at TMS at a rising edge of TCK for the given state transition to occur. IR and DR indicate that the instruction register or the data register is operating in that state.

The TAP controller receives two control inputs (TMS and TCK) and generates control and clock signals for the rest of the test logic architecture. On power-up, the TAP controller enters the Test-Logic-Reset state. To guarantee a reset of the controller from any of the possible states, TMS must remain high for five TCK cycles.

42MX24 and 42MX36 devices support three types of test data registers: bypass, device identification, and boundary scan. The bypass register is selected when no other register needs to be accessed in a device. This speeds up test data transfer to other devices in a test data path. The 32-bit device identification register is a shift register with four fields (lowest significant byte (LSB), ID number, part number and version). The boundary-scan register observes and controls the state of each I/O pin.

Figure 20 • 42MX Timing Model (SRAM Functions)

Note: Values are shown for A42MX36 –3 at 5.0 V worst-case commercial conditions.

3.10.1 Parameter Measurement

The following figures show parameter measurement details.

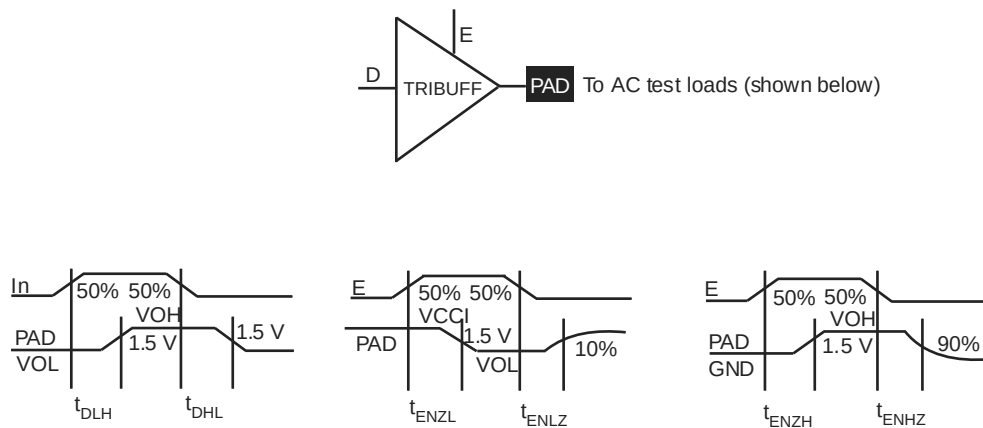
Figure 21 • Output Buffer Delays

Table 37 • A40MX04 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing ⁴												
t _{DLH}	Data-to-Pad HIGH		5.5		6.4		7.2		8.5		11.9	ns
t _{DHL}	Data-to-Pad LOW		4.8		5.5		6.2		7.3		10.2	ns
t _{ENZH}	Enable Pad Z to HIGH		4.7		5.5		6.2		7.3		10.2	ns
t _{ENZL}	Enable Pad Z to LOW		6.8		7.9		8.9		10.5		14.7	ns
t _{ENHZ}	Enable Pad HIGH to Z		11.1		12.8		14.5		17.1		23.9	ns
t _{ENLZ}	Enable Pad LOW to Z		8.2		9.5		10.7		12.6		17.7	ns
d _{TLH}	Delta LOW to HIGH		0.05		0.05		0.06		0.07		0.10	ns/pF
d _{THL}	Delta HIGH to LOW		0.03		0.03		0.04		0.04		0.06	ns/pF

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
2. Set-up times assume fanout of 3. Further testing information can be obtained from the Timer utility.
3. The hold time for the DFME1A macro may be greater than 0 ns. Use the Timer tool from the Designer software to check the hold time for this macro.
4. Delays based on 35 pF loading.

Table 38 • A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Propagation Delays ¹												
t _{PD1}	Single Module		1.2		1.3		1.5		1.8		2.5	ns
t _{CO}	Sequential Clock-to-Q		1.3		1.4		1.6		1.9		2.7	ns
t _{GO}	Latch G-to-Q		1.2		1.4		1.6		1.8		2.6	ns
t _{RS}	Flip-Flop (Latch) Reset-to-Q		1.2		1.6		1.8		2.1		2.9	ns
Logic Module Predicted Routing Delays ²												
t _{RD1}	FO = 1 Routing Delay		0.7		0.8		0.9		1.0		1.4	ns
t _{RD2}	FO = 2 Routing Delay		0.9		1.0		1.2		1.4		1.9	ns
t _{RD3}	FO = 3 Routing Delay		1.2		1.3		1.5		1.7		2.4	ns
t _{RD4}	FO = 4 Routing Delay		1.4		1.5		1.7		2.0		2.9	ns
t _{RD8}	FO = 8 Routing Delay		2.3		2.6		2.9		3.4		4.8	ns
Logic Module Sequential Timing ^{3, 4}												
t _{SUD}	Flip-Flop (Latch) Data Input Set-Up	0.3		0.4		0.4		0.5		0.7		ns
t _{HD}	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.4		0.5		0.5		0.6		0.8		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	3.4		3.8		4.3		5.0		7.0		ns

Table 40 • A42MX16 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{PWL}	Minimum Pulse Width LOW	FO = 32	3.2		3.5		4.0		4.7		6.6		ns
		FO = 384	3.7		4.1		4.6		5.4		7.6		ns
t _{CKSW}	Maximum Skew	FO = 32		0.3		0.4		0.4		0.5		0.7	ns
		FO = 384		0.3		0.4		0.4		0.5		0.7	ns
t _{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
		FO = 384	0.0		0.0		0.0		0.0		0.0		ns
t _{HEXT}	Input Latch External Hold	FO = 32	2.8		3.1		5.5		4.1		5.7		ns
		FO = 384	3.2		3.5		4.0		4.7		6.6		ns
t _P	Minimum Period	FO = 32	4.2		4.67		5.1		5.8		9.7		ns
		FO = 384	4.6		5.1		5.6		6.4		10.7		ns
f _{MAX}	Maximum Frequency	FO = 32		237		215		198		172		103	MHz
		FO = 384		215		195		179		156		94	MHz

Table 40 • A42MX16 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL Output Module Timing ⁴												
t _{DLH}	Data-to-Pad HIGH	2.5		2.8		3.2		3.7		5.2		ns
t _{DHL}	Data-to-Pad LOW	3.0		3.3		3.7		4.4		6.1		ns
t _{ENZH}	Enable Pad Z to HIGH	2.7		3.0		3.4		4.0		5.6		ns
t _{ENZL}	Enable Pad Z to LOW	3.0		3.3		3.8		4.4		6.2		ns
t _{ENHZ}	Enable Pad HIGH to Z	5.4		6.0		6.8		8.0		11.2		ns
t _{ENLZ}	Enable Pad LOW to Z	5.0		5.6		6.3		7.4		10.4		ns
t _{GLH}	G-to-Pad HIGH	2.9		3.2		3.6		4.3		6.0		ns
t _{GHL}	G-to-Pad LOW	2.9		3.2		3.6		4.3		6.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading	5.7		6.3		7.1		8.4		11.9		ns
t _{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading	8.0		8.9		10.1		11.9		16.7		ns
d _{TLH}	Capacitive Loading, LOW to HIGH	0.03		0.03		0.03		0.04		0.06		ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW	0.04		0.04		0.04		0.05		0.07		ns/pF

Table 44 • A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH		3.5		3.9		4.5		5.2		7.3	ns
t _{DHL}	Data-to-Pad LOW		2.5		2.7		3.1		3.6		5.1	ns
t _{ENZH}	Enable Pad Z to HIGH		2.7		3.0		3.3		3.9		5.5	ns
t _{ENZL}	Enable Pad Z to LOW		2.9		3.3		3.7		4.3		6.1	ns
t _{ENHZ}	Enable Pad HIGH to Z		5.3		5.8		6.6		7.8		10.9	ns
t _{ENLZ}	Enable Pad LOW to Z		4.9		5.5		6.2		7.3		10.2	ns
t _{GLH}	G-to-Pad HIGH		5.0		5.6		6.3		7.5		10.4	ns
t _{GHL}	G-to-Pad LOW		5.0		5.6		6.3		7.5		10.4	ns
t _{LSU}	I/O Latch Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t _{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		5.7		6.3		7.1		8.4		11.8	ns
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.8		8.6		9.8		11.5		16.1	ns
d _{TLH}	Capacitive Loading, LOW to HIGH		0.07		0.08		0.09		0.10		0.14	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW		0.07		0.08		0.09		0.10		0.14	ns/pF

1. For dual-module macros, use t_{PD1} + t_{RD1} + t_{PDn}, t_{CO} + t_{RD1} + t_{PDn}, or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading.

Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Combinatorial Functions ¹												
t _{PD}	Internal Array Module Delay		1.9		2.1		2.3		2.7		3.8	ns
t _{PDD}	Internal Decode Module Delay		2.2		2.5		2.8		3.3		4.7	ns
Logic Module Predicted Routing Delays ²												
t _{RD1}	FO = 1 Routing Delay		1.3		1.5		1.7		2.0		2.7	ns
t _{RD2}	FO = 2 Routing Delay		1.8		2.0		2.3		2.7		3.7	ns
t _{RD3}	FO = 3 Routing Delay		2.3		2.5		2.8		3.4		4.7	ns
t _{RD4}	FO = 4 Routing Delay		2.8		3.1		3.5		4.1		5.7	ns

Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description	–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{RD5} FO = 8 Routing Delay		4.6		5.2		5.8		6.9		9.6	ns
t _{RDD} Decode-to-Output Routing Delay		0.5		0.5		0.6		0.7		1.0	ns
Logic Module Sequential Timing^{3, 4}											
t _{CO} Flip-Flop Clock-to-Output		1.8		2.0		2.3		2.7		3.7	ns
t _{GO} Latch Gate-to-Output		1.8		2.0		2.3		2.7		3.7	ns
t _{SUD} Flip-Flop (Latch) Set-Up Time	0.4		0.5		0.6		0.7		0.9		ns
t _{HD} Flip-Flop (Latch) Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t _{RO} Flip-Flop (Latch) Reset-to-Output		2.2		2.4		2.7		3.2		4.5	ns
t _{SUENA} Flip-Flop (Latch) Enable Set-Up	1.0		1.1		1.2		1.4		2.0		ns
t _{HENA} Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA} Flip-Flop (Latch) Clock Active Pulse Width	4.6		5.2		5.8		6.9		9.6		ns
t _{WASYN} Flip-Flop (Latch) Asynchronous Pulse Width	6.1		6.8		7.7		9.0		12.6		ns
Synchronous SRAM Operations											
t _{RC} Read Cycle Time		9.5		10.5		11.9		14.0		19.6	ns
t _{WC} Write Cycle Time		9.5		10.5		11.9		14.0		19.6	ns
t _{RCKHL} Clock HIGH/LOW Time		4.8		5.3		6.0		7.0		9.8	ns
t _{RCO} Data Valid After Clock HIGH/LOW		4.8		5.3		6.0		7.0		9.8	ns
t _{ADSU} Address/Data Set-Up Time	2.3		2.5		2.8		3.4		4.8		ns

Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Predicted Routing Delays ²													
t _{IRD1}	FO = 1 Routing Delay		2.8		3.1		3.5		4.1		5.7		ns
t _{IRD2}	FO = 2 Routing Delay		3.2		3.5		4.1		4.8		6.7		ns
t _{IRD3}	FO = 3 Routing Delay		3.7		4.1		4.7		5.5		7.7		ns
t _{IRD4}	FO = 4 Routing Delay		4.2		4.6		5.3		6.2		8.7		ns
t _{IRD8}	FO = 8 Routing Delay		6.1		6.8		7.7		9.0		12.6		ns
Global Clock Network													
t _{CKH}	Input LOW to HIGH	FO = 32	4.6		5.1		5.7		6.7		9.3		ns
		FO = 635	5.0		5.6		6.3		7.4		10.3		ns
t _{CKL}	Input HIGH to LOW	FO = 32	5.3		5.9		6.7		7.8		11.0		ns
		FO = 635	6.8		7.6		8.6		10.1		14.1		ns
t _{PWH}	Minimum Pulse Width HIGH	FO = 32	2.5		2.7		3.1		3.6		5.1		ns
		FO = 635	2.8		3.1		3.5		4.1		5.7		ns
t _{PWL}	Minimum Pulse Width LOW	FO = 32	2.5		2.7		3.1		3.6		5.1		ns
		FO = 635	2.8		3.1		3.5		4.1		5.7		ns
t _{CKSW}	Maximum Skew	FO = 32	1.0		1.2		1.3		1.5		2.2		ns
		FO = 635	1.0		1.2		1.3		1.5		2.2		ns
t _{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
		FO = 635	0.0		0.0		0.0		0.0		0.0		ns
t _{HEXT}	Input Latch External Hold	FO = 32	4.0		4.4		5.0		5.9		8.2		ns
		FO = 635	4.6		5.2		5.9		6.9		9.6		ns
t _P	Minimum Period (1/f _{MAX})	FO = 32	9.2		10.2		11.1		12.7		21.2		ns
		FO = 635	9.9		11.0		12.0		13.8		23.0		ns
f _{MAX}	Maximum Datapath Frequency	FO = 32	108		98		90		79		47		MHz
		FO = 635	100		91		83		73		44		MHz
TTL Output Module Timing ⁵													
t _{DLH}	Data-to-Pad HIGH		3.6		4.0		4.5		5.3		7.4		ns
t _{DHL}	Data-to-Pad LOW		4.2		4.6		5.2		6.2		8.6		ns
t _{ENZH}	Enable Pad Z to HIGH		3.7		4.2		4.7		5.5		7.7		ns
t _{ENZL}	Enable Pad Z to LOW		4.1		4.6		5.2		6.1		8.5		ns
t _{ENHZ}	Enable Pad HIGH to Z		7.34		8.2		9.3		10.9		15.3		ns
TTL Output Module Timing ⁵													
t _{ENLZ}	Enable Pad LOW to Z		6.9		7.6		8.7		10.2		14.3		ns
t _{GLH}	G-to-Pad HIGH		4.9		5.5		6.2		7.3		10.2		ns
t _{GHL}	G-to-Pad LOW		4.9		5.5		6.2		7.3		10.2		ns
t _{LSU}	I/O Latch Output Set-Up		0.7		0.7		0.8		1.0		1.4		ns
t _{LH}	I/O Latch Output Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.9		8.8		10.0		11.8		16.5		ns

Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{ACO} Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		10.9		12.1		13.7		16.1		22.5	ns
d _{TLH} Capacitive Loading, LOW to HIGH		0.10		0.11		0.12		0.14		0.20	ns/pF
d _{THL} Capacitive Loading, HIGH to LOW		0.10		0.11		0.12		0.14		0.20	ns/pF
CMOS Output Module Timing⁵											
t _{DLH} Data-to-Pad HIGH		4.9		5.5		6.2		7.3		10.3	ns
t _{DHL} Data-to-Pad LOW		3.4		3.8		4.3		5.1		7.1	ns
t _{ENZH} Enable Pad Z to HIGH		3.7		4.1		4.7		5.5		7.7	ns
t _{ENZL} Enable Pad Z to LOW		4.1		4.6		5.2		6.1		8.5	ns
t _{ENHZ} Enable Pad HIGH to Z		7.4		8.2		9.3		10.9		15.3	ns
t _{ENLZ} Enable Pad LOW to Z		6.9		7.6		8.7		10.2		14.3	ns
t _{GLH} G-to-Pad HIGH		7.0		7.8		8.9		10.4		14.6	ns
t _{GHL} G-to-Pad LOW		7.0		7.8		8.9		10.4		14.6	ns
t _{LSU} I/O Latch Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t _{LH} I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO} I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.9		8.8		10.0		11.8		16.5	ns

1. For dual-module macros, use t_{PD1} + t_{RD1} + t_{PDn}, t_{CO} + t_{RD1} + t_{PDn}, or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading.

3.12 Pin Descriptions

This section lists the pin descriptions for 40MX and 42MX series FPGAs.

CLK/A/B, I/O Global Clock

Clock inputs for clock distribution networks. CLK is for 40MX while CLKA and CLKB are for 42MX devices. The clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

DCLK, I/O Diagnostic Clock

Clock input for diagnostic probe and device programming. DCLK is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

GND, Ground

Input LOW supply voltage.

I/O, Input/Output

Table 51 • PQ144

PQ144	
Pin Number	A42MX09 Function
43	I/O
44	GNDQ
45	GNDI
46	NC
47	I/O
48	I/O
49	I/O
50	I/O
51	I/O
52	I/O
53	I/O
54	VCC
55	VCCI
56	NC
57	I/O
58	I/O
59	I/O
60	I/O
61	I/O
62	I/O
63	I/O
64	GND
65	GNDI
66	I/O
67	I/O
68	I/O
69	I/O
70	I/O
71	SDO
72	I/O
73	I/O
74	I/O
75	I/O
76	I/O
77	I/O
78	I/O
79	GNDQ

Table 52 • PQ160

PQ160			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
132	I/O	I/O	I/O
133	I/O	I/O	I/O
134	I/O	I/O	I/O
135	NC	VCCA	VCCA
136	I/O	I/O	I/O
137	I/O	I/O	I/O
138	NC	VCCA	VCCA
139	VCCI	VCCI	VCCI
140	GND	GND	GND
141	NC	I/O	I/O
142	I/O	I/O	I/O
143	I/O	I/O	I/O
144	I/O	I/O	I/O
145	GND	GND	GND
146	NC	I/O	I/O
147	I/O	I/O	I/O
148	I/O	I/O	I/O
149	I/O	I/O	I/O
150	NC	VCCA	VCCA
151	NC	I/O	I/O
152	NC	I/O	I/O
153	NC	I/O	I/O
154	NC	I/O	I/O
155	GND	GND	GND
156	I/O	I/O	I/O
157	I/O	I/O	I/O
158	I/O	I/O	I/O
159	MODE	MODE	MODE
160	GND	GND	GND

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
15	QCLKC, I/O
16	I/O
17	WD, I/O
18	WD, I/O
19	I/O
20	I/O
21	WD, I/O
22	WD, I/O
23	I/O
24	PRB, I/O
25	I/O
26	CLKB, I/O
27	I/O
28	GND
29	VCCA
30	VCCI
31	I/O
32	CLKA, I/O
33	I/O
34	PRA, I/O
35	I/O
36	I/O
37	WD, I/O
38	WD, I/O
39	I/O
40	I/O
41	I/O
42	I/O
43	I/O
44	I/O
45	QCLKD, I/O
46	I/O
47	WD, I/O
48	WD, I/O
49	I/O
50	I/O
51	I/O

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
52	VCCI
53	I/O
54	WD, I/O
55	WD, I/O
56	I/O
57	SDI, I/O
58	I/O
59	VCCA
60	GND
61	GND
62	I/O
63	I/O
64	I/O
65	I/O
66	I/O
67	I/O
68	I/O
69	I/O
70	I/O
71	VCCI
72	I/O
73	I/O
74	I/O
75	I/O
76	I/O
77	I/O
78	I/O
79	I/O
80	I/O
81	I/O
82	I/O
83	I/O
84	I/O
85	VCCA
86	I/O
87	I/O
88	VCCA

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
163	WD, I/O
164	WD, I/O
165	I/O
166	QCLKA, I/O
167	I/O
168	I/O
169	I/O
170	I/O
171	I/O
172	VCCI
173	I/O
174	WD, I/O
175	WD, I/O
176	I/O
177	I/O
178	TDI, I/O
179	TMS, I/O
180	GND
181	VCCA
182	GND
183	I/O
184	I/O
185	I/O
186	I/O
187	I/O
188	I/O
189	I/O
190	I/O
191	I/O
192	VCCI
193	I/O
194	I/O
195	I/O
196	I/O
197	I/O
198	I/O
199	I/O

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
200	I/O
201	I/O
202	I/O
203	I/O
204	I/O
205	I/O
206	VCCA
207	I/O
208	I/O
209	VCCA
210	VCCI
211	I/O
212	I/O
213	I/O
214	I/O
215	I/O
216	I/O
217	I/O
218	I/O
219	VCCA
220	I/O
221	I/O
222	I/O
223	I/O
224	I/O
225	I/O
226	I/O
227	VCCI
228	I/O
229	I/O
230	I/O
231	I/O
232	I/O
233	I/O
234	I/O
235	I/O
236	I/O

Table 57 • TQ176

TQ176			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
121	NC	NC	I/O
122	I/O	I/O	I/O
123	I/O	I/O	I/O
124	NC	I/O	I/O
125	NC	I/O	I/O
126	NC	NC	I/O
127	I/O	I/O	I/O
128	I/O	I/O	I/O
129	I/O	I/O	I/O
130	I/O	I/O	I/O
131	I/O	I/O	I/O
132	I/O	I/O	I/O
133	GND	GND	GND
134	I/O	I/O	I/O
135	SDI, I/O	SDI, I/O	SDI, I/O
136	NC	I/O	I/O
137	I/O	I/O	WD, I/O
138	I/O	I/O	WD, I/O
139	I/O	I/O	I/O
140	NC	VCCI	VCCI
141	I/O	I/O	I/O
142	I/O	I/O	I/O
143	NC	I/O	I/O
144	NC	I/O	WD, I/O
145	NC	NC	WD, I/O
146	I/O	I/O	I/O
147	NC	I/O	I/O
148	I/O	I/O	I/O
149	I/O	I/O	I/O
150	I/O	I/O	WD, I/O
151	NC	I/O	WD, I/O
152	PRA, I/O	PRA, I/O	PRA, I/O
153	I/O	I/O	I/O
154	CLKA, I/O	CLKA, I/O	CLKA, I/O
155	VCCA	VCCA	VCCA
156	GND	GND	GND
157	I/O	I/O	I/O

Table 59 • CQ256

CQ256	
Pin Number	A42MX36 Function
59	I/O
60	VCCA
61	GND
62	GND
63	NC
64	NC
65	NC
66	I/O
67	SDO, TDO, I/O
68	I/O
69	WD, I/O
70	WD, I/O
71	I/O
72	VCCI
73	I/O
74	I/O
75	I/O
76	WD, I/O
77	GND
78	WD, I/O
79	I/O
80	QCLKB, I/O
81	I/O
82	I/O
83	I/O
84	I/O
85	I/O
86	I/O
87	WD, I/O
88	WD, I/O
89	I/O
90	I/O
91	I/O
92	I/O
93	I/O
94	I/O
95	VCCI

Table 59 • CQ256

CQ256	
Pin Number	A42MX36 Function
133	I/O
134	I/O
135	I/O
136	I/O
137	I/O
138	I/O
139	GND
140	I/O
141	I/O
142	I/O
143	I/O
144	I/O
145	I/O
146	I/O
147	I/O
148	I/O
149	I/O
150	I/O
151	I/O
152	I/O
153	I/O
154	I/O
155	VCCA
156	I/O
157	I/O
158	VCCA
159	VCCI
160	GND
161	I/O
162	I/O
163	I/O
164	I/O
165	GND
166	I/O
167	I/O
168	I/O
169	I/O

Table 61 • PG132

PG132	
Pin Number	A42MX09 Function
G12	VSV
F13	I/O
F12	I/O
F11	I/O
F10	I/O
E13	I/O
D13	I/O
D12	I/O
C13	I/O
B13	I/O
D11	I/O
C12	I/O
A13	I/O
C11	I/O
B12	SDI
B11	I/O
C10	I/O
A12	I/O
A11	I/O
B10	I/O
D8	I/O
A10	I/O
C8	I/O
A9	I/O
B8	PRBA
A8	I/O
B7	CLKA
A7	I/O
B6	CLKB
A6	I/O
C6	PRBB
A5	I/O
D6	I/O
A4	I/O
B4	I/O
A3	I/O
C4	I/O